

Conduction mechanisms in cupric oxide films and nanowire networks



Shrividya Ravi, Alan Kaiser, Chris Bumby

Introduction

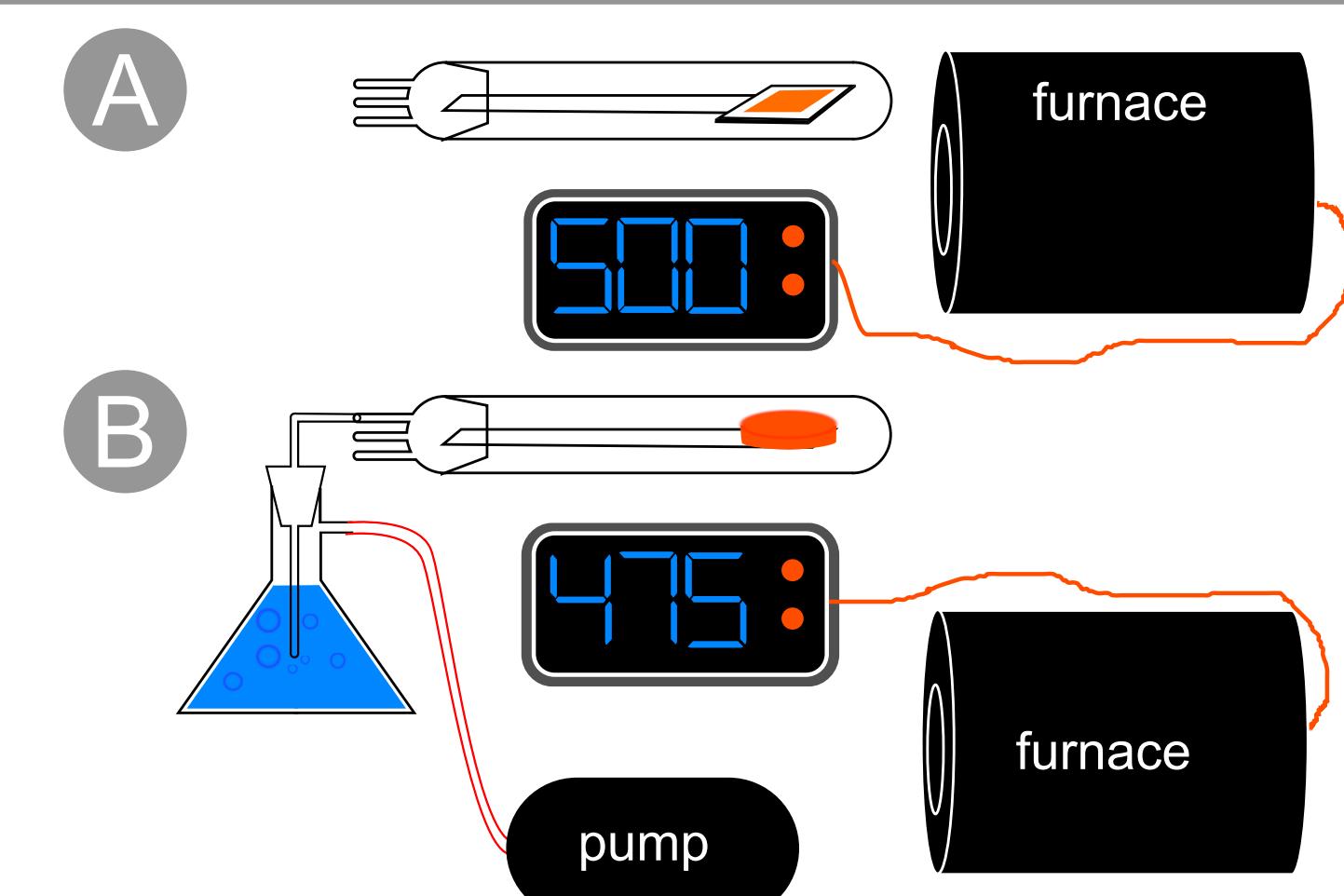
- Cupric Oxide or CuO is a p-type semiconductor with an indirect bandgap between 1.2 eV [1] and 1.40 eV [2]. CuO exhibits mobilities upto $5 \text{ cm}^2 \text{ V}^{-1} \text{ s}^{-1}$ [2].
- CuO nanowires can be fabricated by heating copper foil/ buttons in air [1].
- Our aim is to compare the dominant conduction mechanisms of majority carriers in polycrystalline CuO films ('bulk') and CuO nanowire networks.

Fabrication

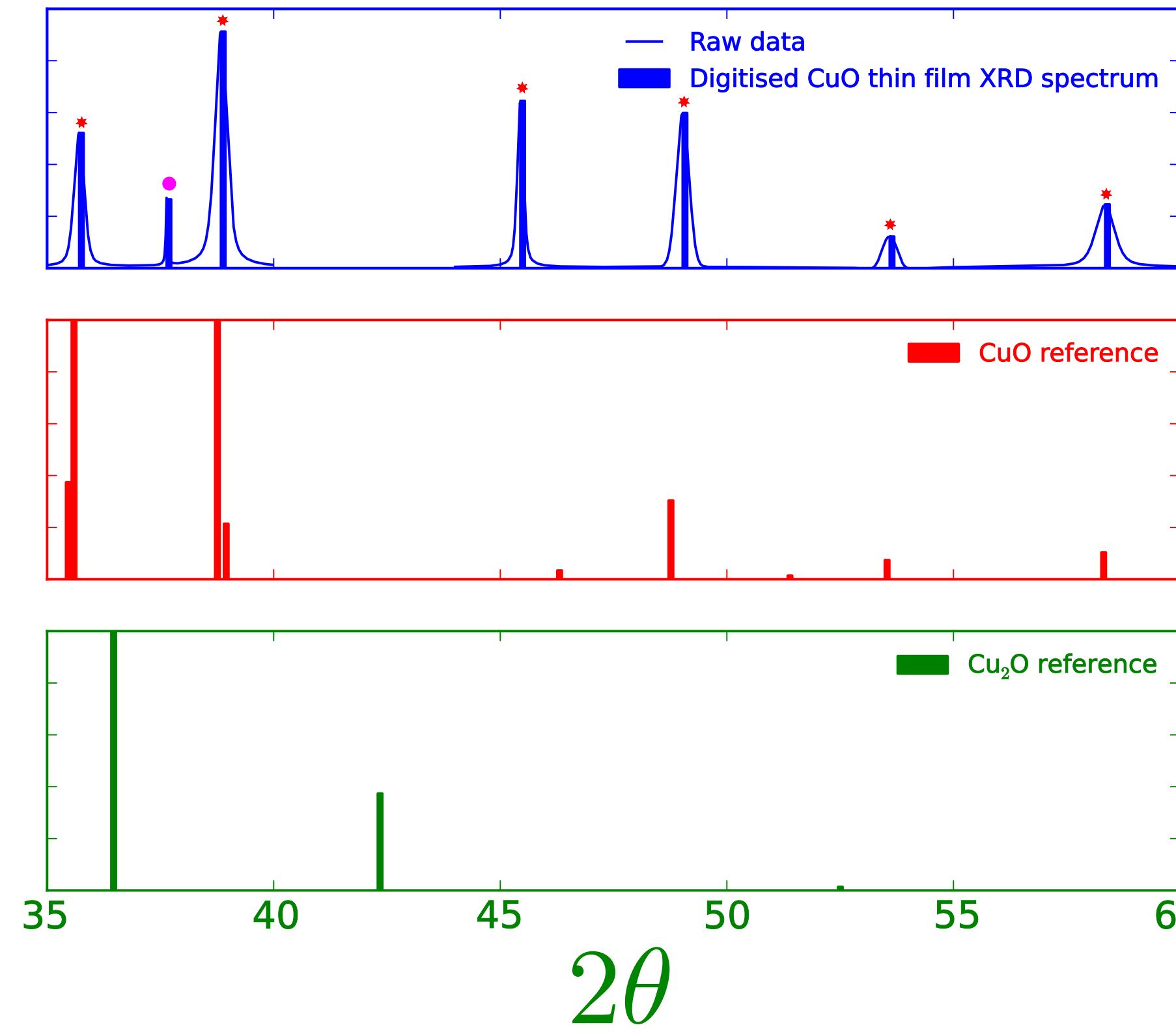
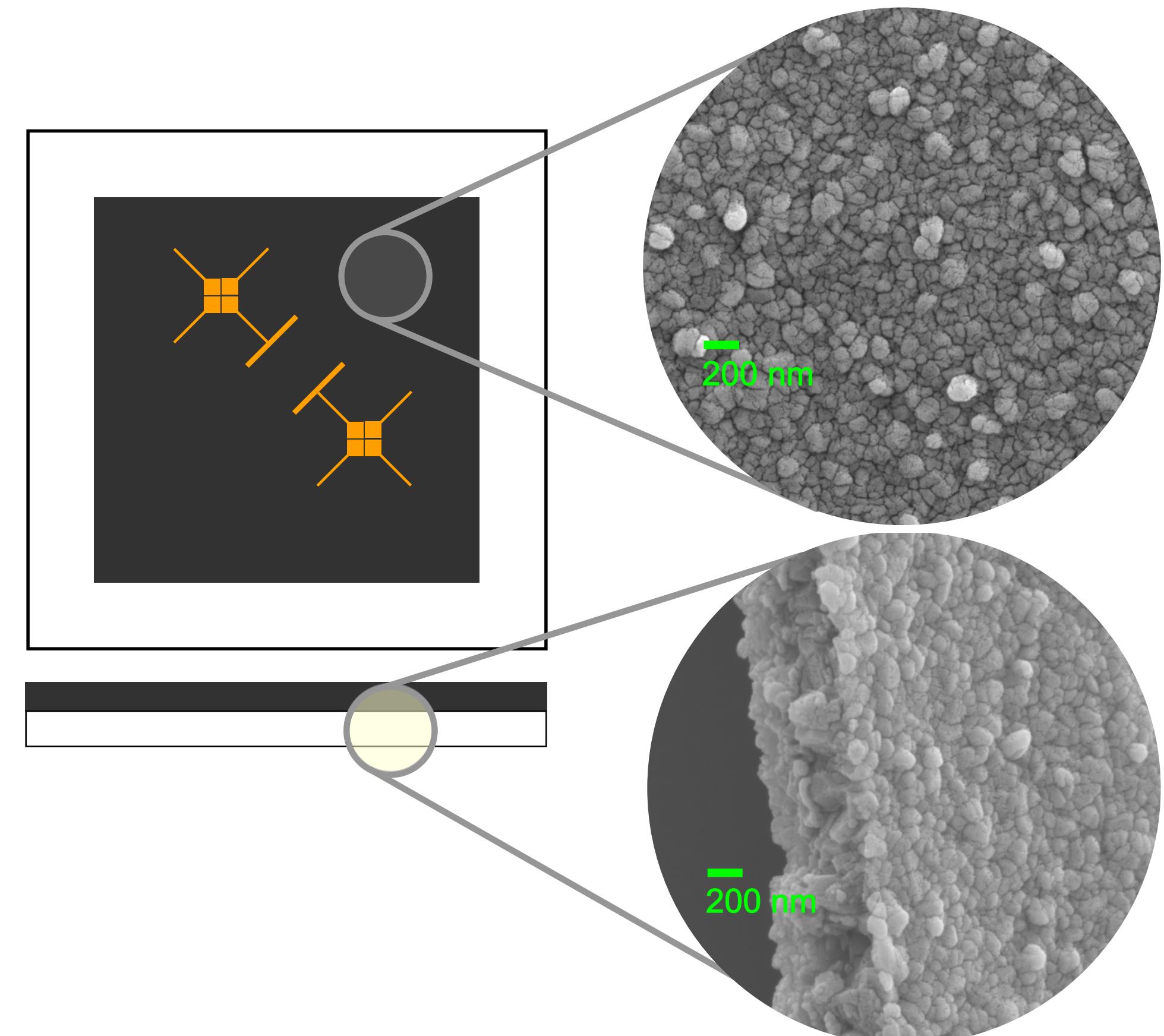
- Fabrication of CuO thin films (A) and nanowires (B) is carried out by thermal oxidation of copper in a tube furnace.

- CuO thin films are made by annealing ~1 micron thick copper (thermally evaporated on sapphire) at 500 C for 2 hours.

- CuO nanowires are made by annealing small copper buttons in 'wet' air at 475 C for ~ 2 hours.

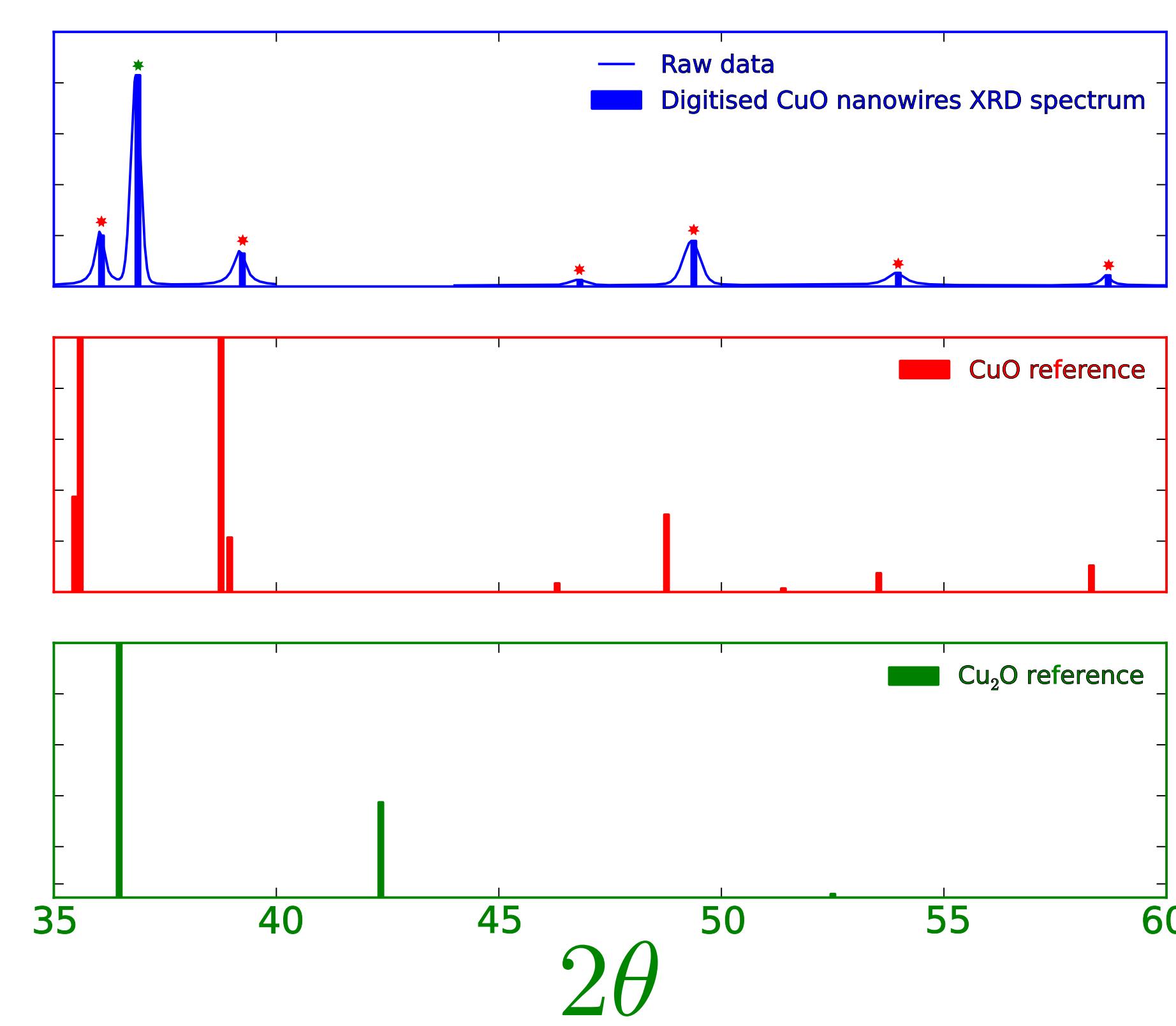
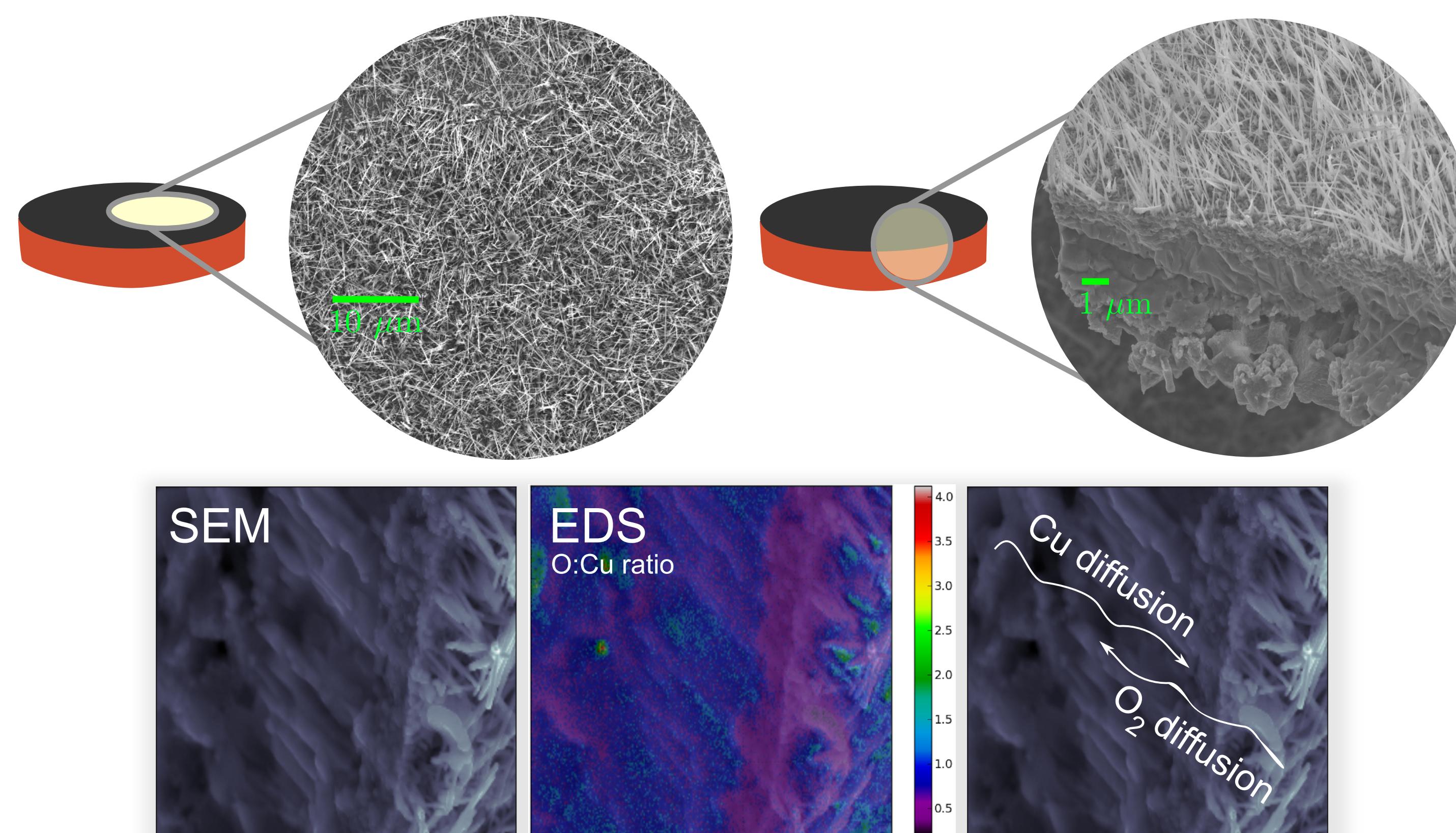


CuO thin films



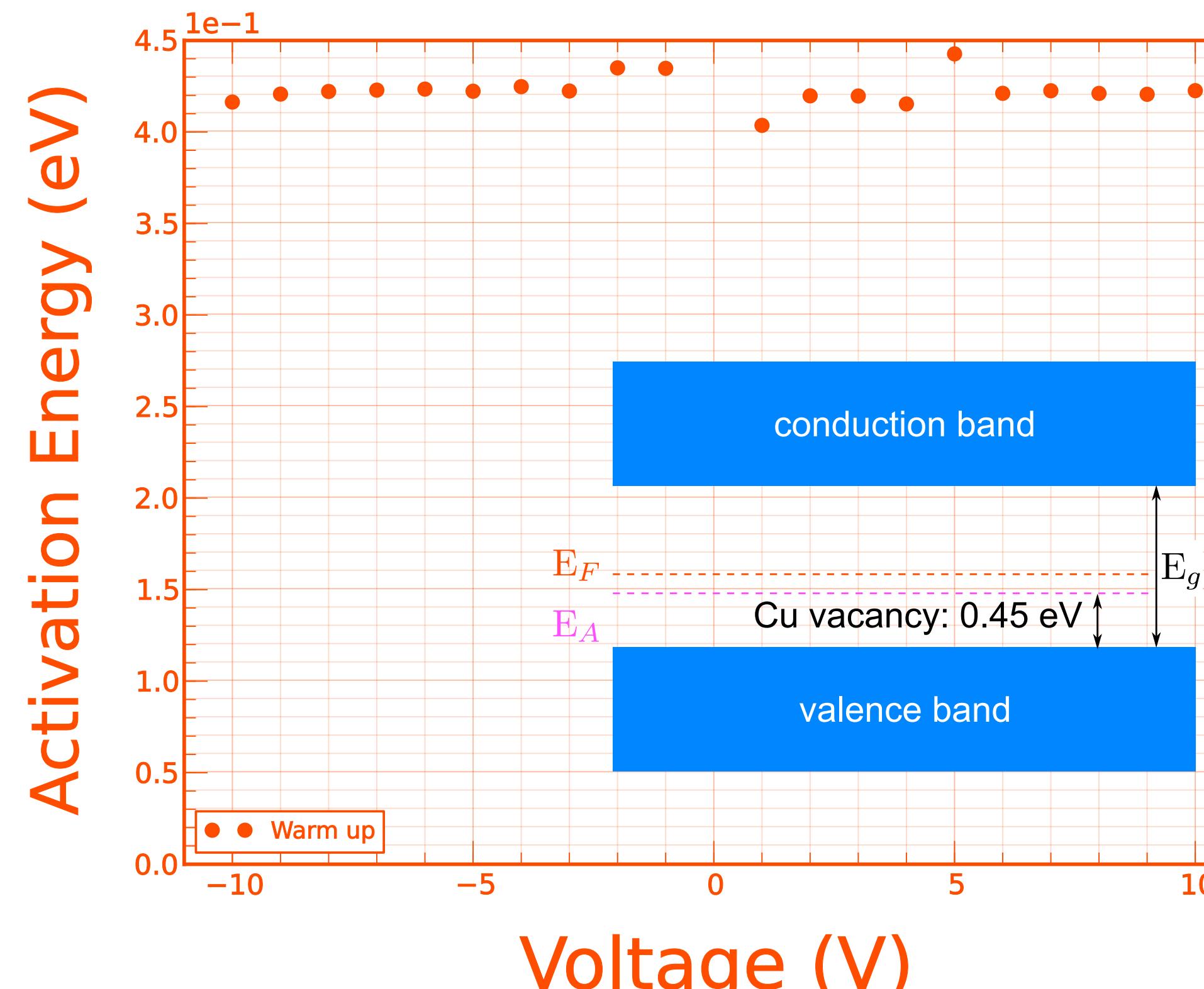
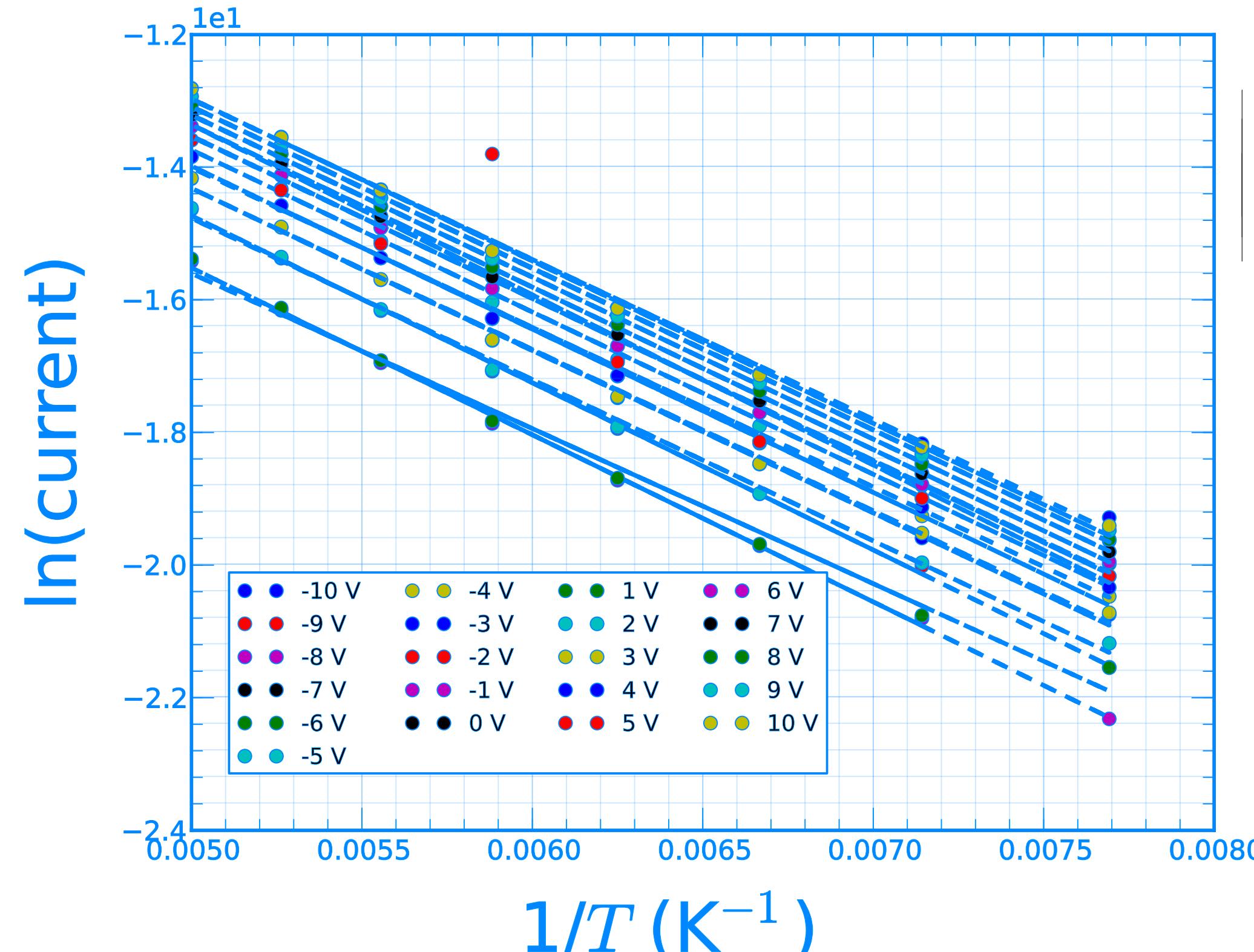
- Scanning electron microscopy (SEM) images on the far left show a clean polycrystalline film.
- The X-ray diffraction (XRD) spectrum was profile-fitted with Pseudo-Voigt or Lorentzian lineshapes. A digitised spectrum was then created from the fitted peak positions and normalised intensities.
- A comparison of the CuO thin film XRD spectrum with reference spectra show that it is entirely comprised of monoclinic CuO. The peak highlighted with a '*' is from the (1,1,0) reflection of the sapphire substrate.
- In order to obtain conduction data from the thin films, a simple two electrode geometry was patterned using photolithography. Chrome/gold contacts (shown in schematic) were thermally evaporated on the exposed pattern before lift-off.

CuO nanowires



- The presence of nanowires after oxidation is indicated by a matt black surface.
- SEM images on the far left show a nanowire forest growing from a thick polycrystalline oxide layer.
- Energy dispersive spectroscopy (EDS) suggests that the bulk of the polycrystalline layers are CuO while the 'seeding' oxide layer is copper rich Cu O₂.
- The digitised XRD spectrum for CuO nanowires shows a mixture of the two phases of copper oxide.

Conduction I



Temperature-dependent current measurements reveal an activation-type behavior for polycrystalline CuO. The average fitted activation energies for a range of different voltages is 422 meV. This value corresponds to activation from a deep level trap state caused by a copper vacancies in the lattice.

Conduction II

